L Number	Hits	Search Text	DB	Time stamp	
-	502	714/733.ccls.	USPAT;	2002/10/24 10:27	
			US-PGPUB;		
			ЕРО; ЈРО;		
			DERWENT,		
			IBM_TDB		
_	12	714/733.ccls. and ((instruction instructions) same (external adj (test	USPAT;	2002/10/24 10:31	
		tests tester)))	US-PGPUB;	2002/10/21 10:51	
			ЕРО; ЛРО;		
			DERWENT;		
			IBM TDB		
_	2	5982681.pn.	USPAT;	2002/10/24 10:27	
•		3302001.pm.		2002/10/24 10:37	
		,	US-PGPUB;		
			EPO; JPO;		
			DERWENT;		
	20	714/722	IBM_TDB		
•	29	714/733.ccls. and ((test external) adj (instruction instructions))	USPAT;	2002/10/24 12:53	
			US-PGPUB;		
			ЕРО; ЈРО;		
			DERWENT;		
			IBM_TDB		
	2355	714/718.ccls.	USPAT;	2002/10/24 12:55	
	,	,	US-PGPUB;		
			ЕРО; ЈРО;		
			DERWENT;	·	
			IBM_TDB		
	5	714/718.ccls. and (initialization with (BIST built-in-self-test))	USPAT;	2002/10/24 13:02	
		(US-PGPUB;	2002,10,2113.02	
			EPO; JPO;		
			DERWENT;		
			IBM_TDB		
	0	(5161232,5202978,5291425,5301199,5303199,5355509,5361264,536964	IDM_IDD	1 10 05 1/4 07 207 54 04 4 6 7 5	55040
		(3101232,3202776,3271723,3301177,3303177,3333307,3301204,330704		1 LU,DE 1 1911 DU,DO 1,DO 1911 U 1, 5	JJU4:
		·	US-PGPUB;		
	0	(5161222 5202078 5201425 5201100 5202100 5255500 5261264 526064	DERWENT	1.0000000000000000000000000000000000000	C C O 40
	"	(5161232,5202978,5291425,5301199,5303199,5355509,5361264,536964		1 2U,024 6 7,3	22045
		•	US-PGPUB;	•	
			EPO; JPO;		
-54			DERWENT;		
			IBM_TDB	i	
	23	(5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264,	USPAT;	2002/10/30 16:05	
		5369648, 5398250, 5448110, 5459737, 5485467,	US-PGPUB;		
		5504903,5509019,555308,5619512,5640509,5668816,5802071).pn.	ЕРО; ЛРО;		
			DERWENT;		
			IBM_TDB		
,	40	(5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264,	USPĀT;	2002/10/30 16:06	
		5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019,	US-PGPUB;		
		555308, 5619512, 5640509, 5668816, "5802071").pn.	ЕРО; ЛРО;		
			DERWENT;		
			IBM_TDB		
,	229	(5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619,	USPAT;	2002/10/30 16:08	
		5771241, 5898703, 5396498, "4433413"),pn	US-PGPUB;	2002/10/30 10:00	
			DERWENT		
	229	(5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619,	USPAT;	2002/10/30 16:08	
	243	5771241, 5898703, 5396498, "4433413").pn		2002/10/30 10:08	
		2111271, 2020102, 2220720, 9933913).pm	US-PGPUB;		
	_	((5161222 5202079 5201425 5201100 5202100 5255500 5265	DERWENT	2002/10/20 3 5 5 5	
	2	((5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264,	USPAT;	2002/10/30 16:10	
		5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019,	US-PGPUB;		
`		555308, 5619512, 5640509, 5668816, "5802071").pn.) and ((5961653,	DERWENT		
		5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241,			
		5898703, 5396498, "4433413").pn)			

-	267	((5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264, 5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019, 555308, 5619512, 5640509, 5668816, "5802071").pn.) ((5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241, 5898703, 5396498, "4433413").pn)	USPAT; US-PGPUB; DERWENT	2002/10/30 16:09
-	2	5982681.pn.	USPAT; US-PGPUB;	2002/10/31 16:47
-	2	5982681.pn.	DERWENT USPAT; US-PGPUB; EPO; JPO;	2003/03/26 16:40
-	420	((manufactur\$3 and (board system circuit chip)) with test\$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/06/24 16:10
-	39	((((manufactur\$3 and (board system circuit chip)) with test\$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")).ab.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/06/24 15:04
-	12288095	US 5539652.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/06/24 15:05
-	2	5539652.pn.	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO, JPO;	2003/06/24 16:07
-	348	((manufactur\$3 and (board system chip)) with test\$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/06/24 16:14
-	, 4	(((manufactur\$3 and (board system circuit chip)) with test\$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")).ti.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/06/24 16:15
-	18	((manufactur\$3 and (board system chip)) with test\$3) same (BIST self-test "self test" "built-in-self-test" "built in self test").ab.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/06/24 16:17
1	305	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/11/20 13:02
-	5	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufacture and board) near (level test))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/11/20 13:00
-	32	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur\$3 and board) near (level test))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:00

-	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:01
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/724.ccls.	ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:01
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/734.ccls.	EPO; JPO;	9
•			DERWENT;	
		. *	IBM_TDB	
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:01
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/742.ccls.	ЕРО; ЛРО;	
			DERWENT;	
			IBM_TDB	
- *	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:01
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/735.ccls.	ЕРО; ЛРО;	
			DERWENT,	
			IBM TDB	
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPĀT;	2003/11/20 13:01
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
	•	((manufactur\$3 and board) near (level test))) and 714/736.ccls.	ЕРО; ЛРО;	
			DERWENT;	
			IBM TDB	
_	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPĀT;	2003/11/20 13:02
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/737.ccls.	ЕРО; ЈРО;	
		, , , , , , , , , , , , , , , , , , , ,	DERWENT;	· ·
			IBM TDB	,
-	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:02
		(memory cache FLASH RAM ROM DRAM SRAM CAM)) and	US-PGPUB;	
		((manufactur\$3 and board) near (level test))) and 714/733.ccls.	ЕРО; ЛРО;	
		, , , , , , , , , , , , , , , , , , , ,	DERWENT;	
			IBM_TDB	
-	. 1	((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPĀT;	2003/11/20 13:02
		(memory cache FLASH RAM ROM DRAM SRAM CAM) with	US-PGPUB;	
		(manufacture and board)) and 714/733.ccls.	ЕРО; ЛРО;	
		<i>"</i>	DERWENT;	*
			IBM TDB	
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:02
		(memory cache FLASH RAM ROM DRAM SRAM CAM) with	US-PGPUB;	
		(manufacture and board)) and 714/734.ccls.	ЕРО; ЛРО;	
		<i>"</i>	DERWENT;	•
			IBM TDB	
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPĀT;	2003/11/20 13:03
		(memory cache FLASH RAM ROM DRAM SRAM CAM) with	US-PGPUB;	
		(manufacture and board)) and 714/724.ccls.	ЕРО; ЈРО;	
		"	DERWENT;	
			IBM_TDB	,
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:03
		(memory cache FLASH RAM ROM DRAM SRAM CAM) with	US-PGPUB;	
		(manufacture and board)) and 714/742.ccls.	ЕРО; ЛРО;	
		, , , , , , , , , , , , , , , , , , ,	DERWENT;	
			IBM TDB	
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with	USPAT;	2003/11/20 13:03
		(memory cache FLASH RAM ROM DRAM SRAM CAM) with	US-PGPUB;	2000/11/20 10:00
		(manufacture and board)) and 714/724.ccls.	ЕРО; ЛРО;	
		,	DERWENT;	
	- 1		IBM_TDB	
	1		1	